

IN THE U. S. PATENT AND TRADEMARK OFFICE

In re application of

Iiro HIETANEN et al.

Conf. 6321

Application No. 10/533,645

Group 2877

Filed: January 13, 2006

Examiner Rebecca Slomski

Title: SYNCHRONOUS OPTICAL MEASUREMENT
AND INSPECTION METHOD AND MEANS

AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

April 22, 2009

Sir:

In response to the non-final Office Action mailed January 22, 2009, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 12 of this paper.